

<b>Notice of References Cited</b>	Application/Control No. 10/823,558	Applicant(s)/Patent Under Reexamination WADE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,257,943	11-1993	Ueno et al.	439/164
	B	US-5,310,356	05-1994	Obata et al.	439/169
	C	US-5,314,344	05-1994	Ida et al.	439/164
	D	US-5,409,389	04-1995	Shibata et al.	439/164
	E	US-5,637,005	06-1997	Bannai et al.	439/164
	F	US-6,299,453	10-2001	Matsumoto, Tsuyoshi	439/15
	G	US-6,471,529	10-2002	Oishi, Hiroshi	439/164
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000048924 A	02-2000	Japan	KOYATA et al.	H01R 35/04
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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